

Defect oriented fault coverage of 100stuck-at fault test sets

Blyzniuk, M.; Cibakova, Tatiana; Gramatova, Elena; Kuzmich, W.; Lobur, M.; Pleskacz, Witold A.; **Raik, Jaan; Ubar, Raimund-Johannes** Proceedings of the 7th International Conference Mixed Design of Integrated Circuits and Systems : MIXDES 2000 : Gdynia, Poland, 15-17 June 2000 2000 / p. 511-516 : ill <https://repo.pw.edu.pl/info/seam?ps=20&id=WUT7e20f35d67ae45d3b2d1264d7a4ba722&en&pn=1&cid=156607>